

REMARKS

Claims 4, 27, 28, and 34-67 have been cancelled without prejudice, claims 1, 3, and 29 have been amended, and claims 68 and 69 have been newly added. Claims 1, 3, 6-12, 14-26, 29-33, 68, and 69 are now pending in the application. Applicants respectfully request reexamination and reconsideration of the application as amended.

The claims have been rejected in view of one or more of U.S. Patent Nos. 5,949,242; 5,131,535; 6,147,316; 5,528,825; 6,184,699; 6,264,533; and 6,264,533.

Independent claim 1 recites a method in which a plurality of singulated semiconductor dice placed in a carrier and tested. Results of the testing for each die in the carrier are stored in a digital storage device on the carrier. None of the cited references, whether taken singly or in combination, teaches or suggests storing in a digital storage device on a carrier information regarding testing of each of a plurality of singulated dice in the carrier. Therefore, independent claim 1 patentably distinguishes over the cited references.

Claims 3, 6-12, 14-26, 29-33, 68, and 69 depend directly or indirectly from claim 1 and therefore patentably distinguish over the cited references for the same reason as claim 1. In addition, these dependent claims recite further elements that distinguish over the cited references. For example, the cited references fail to teach or suggest "constructing using data stored in said digital storage device a map of a semiconductor wafer from which at least two of said dice were singulated indicating a location on said wafer of each of said dice and an indication of whether each said die passed or failed said testing" as now recited in claim 69. Therefore, the dependent claims further distinguish over the cited references.

In view of the foregoing, Applicants respectfully submit that the application is in condition for allowance. If the Examiner believes that a telephone conference with Applicants' attorney would be helpful, the Examiner is invited to telephone the undersigned at (925) 456-3915.

Although Applicants believe that all necessary extensions of time and fees have been provided for, Applicants petition the Director for any extension of time deemed necessary for acceptance of this submission, and Applicants authorize the Director to charge any fee deemed necessary for acceptance of this submission to Deposit Account No. 50-0285 (order no. P90-US).

Respectfully submitted,

Date: August 14, 2002

By: 

N. Kenneth Burraston
Reg. No. 39,923

FormFactor, Inc.
Legal Department
2140 Research Dr.
Livermore, CA 94550
Telephone: (925) 456-3915

VERSION WITH MARKINGS TO SHOW CHANGES

1. (Twice Amended) A method comprising:

[singulating at least one semiconductor wafer into a plurality of singulated dice, each said dice comprising an integrated circuit;

applying an identification code to a carrier, said identification code identifying each of a plurality of said singulated dice;]

depositing [said] a plurality of [said] singulated dice [unpackaged] into [said] a carrier, said carrier comprising a digital storage device; [and]

testing said singulated dice while deposited in said carrier; and

storing in said digital storage device data indicating results of said testing of each of said dice.

3. (Twice Amended) A method as in claim 1 further comprising storing an identification code in said digital storage device, wherein said identification code comprises information identifying [said] at least one semiconductor wafer from which said dice were singulated.

29. (Twice Amended) A method as in claim [27] 1 further comprising:

mounting, prior to said testing, a plurality of elongate, resilient electrical contact elements on contact pads of said dice;

mounting, prior to said testing, said carrier onto a substrate having a plurality of electrical contact pads, wherein each of said contact pads on said dice are electrically coupled to a corresponding one of said plurality of electrical contact pads on said substrate through a corresponding one of said elongate, resilient electrical contact elements.